

ILC-HiGrade 3rd scientific workshop

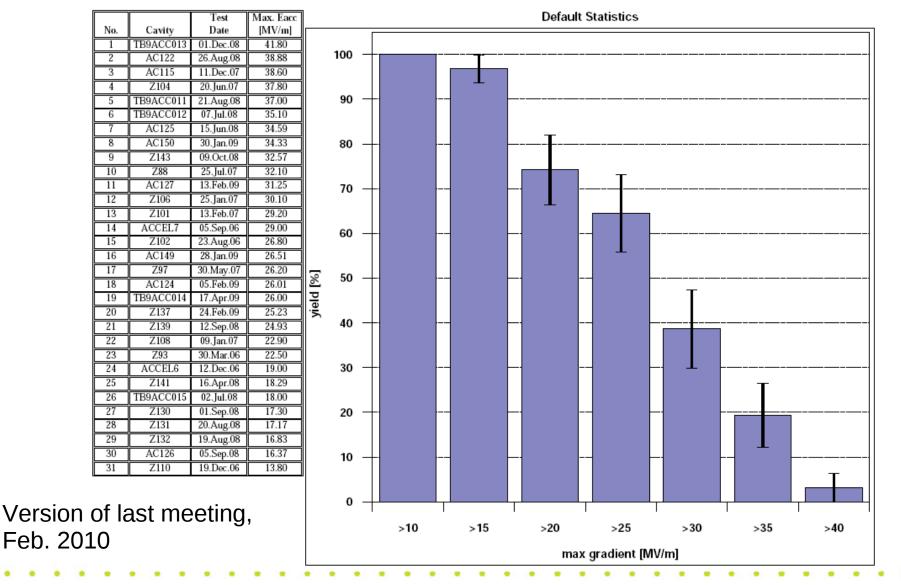
Optical Mapping

S. Aderhold

DESY

3rd ILC-HiGrade Meeting DESY 22.11.2010

ILC cavity yield



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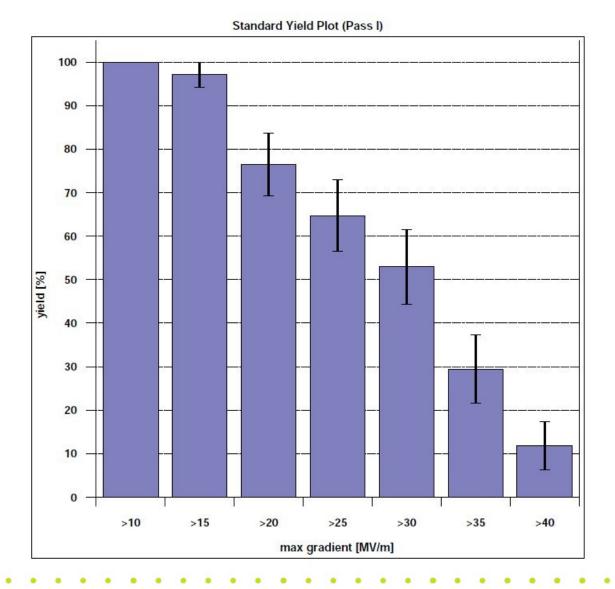
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ILC cavity yield, 1st pass

 Some additional cavities

IIL

 1st pass yield slightly improved



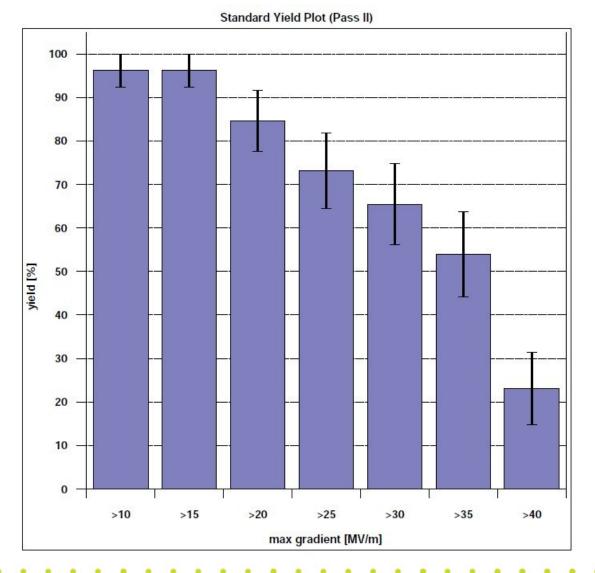
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ILC cavity yield, 2nd pass

 Improvement towards ILCgoals by 2nd treatment

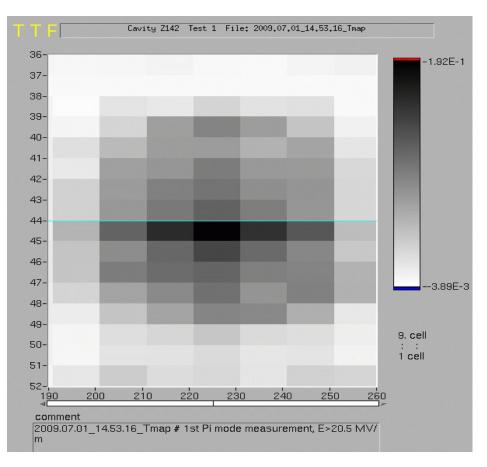
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• We learn what do do!



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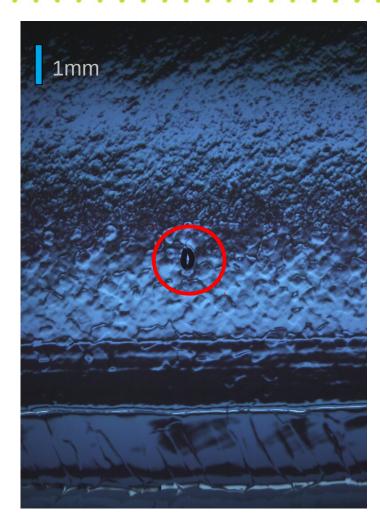
Tmap \leftrightarrow opt. Inspection: Z142



Hotspot during Tmap at equator 6 in pi-mode, Limited at 20.6 MV/m

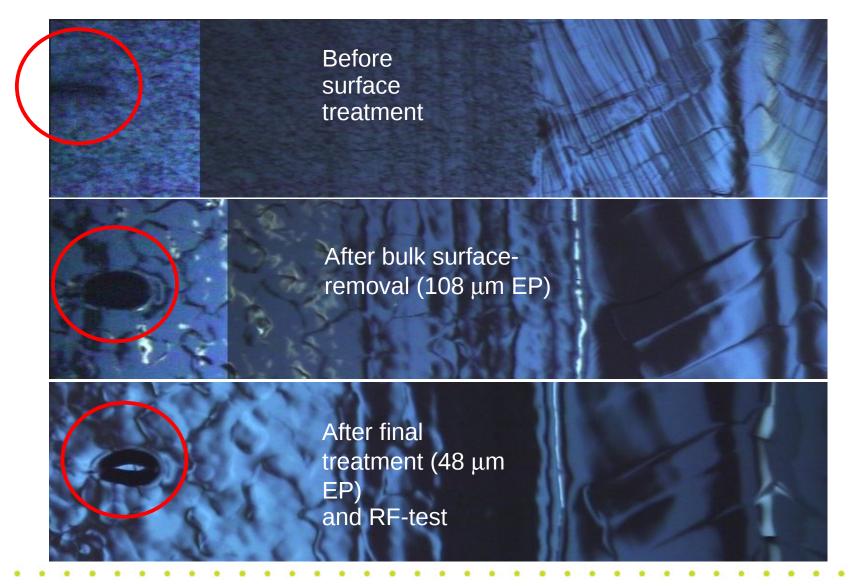
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Optical Mapping S. Aderhold



Same region inside cavity after RF-test

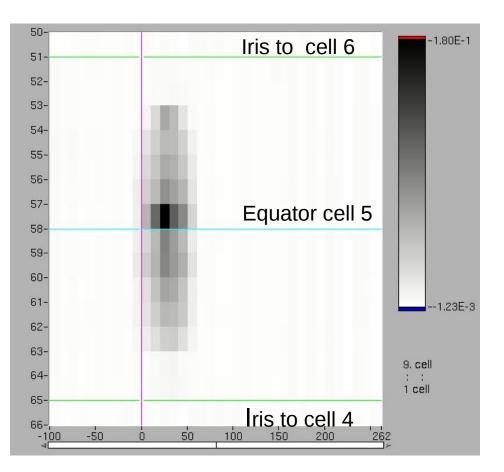
Evolution of defect in Z142



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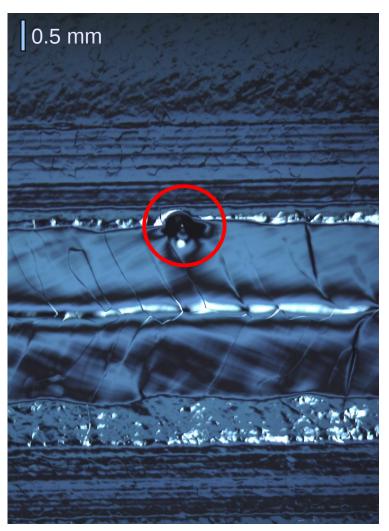
Tmap ↔ opt. Inspection: Z130



Z130: Quench in $3\pi/9$ -mode at 22 MV/m

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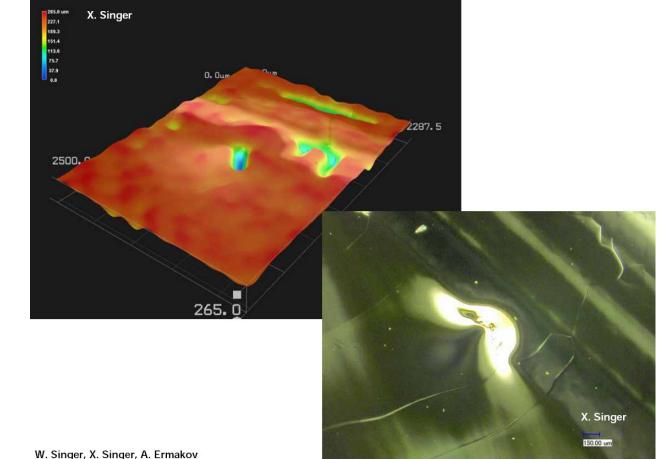
Optical Mapping S. Aderhold



Picture of same location

Defect in Z130

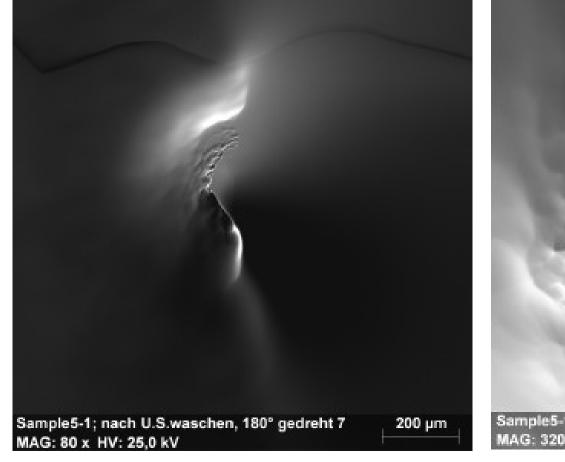
- Cavity has been cut for further investigation
- EDX: no foreign material

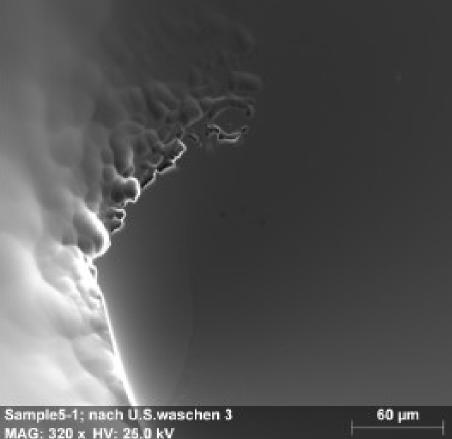


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SEM-picture of defect





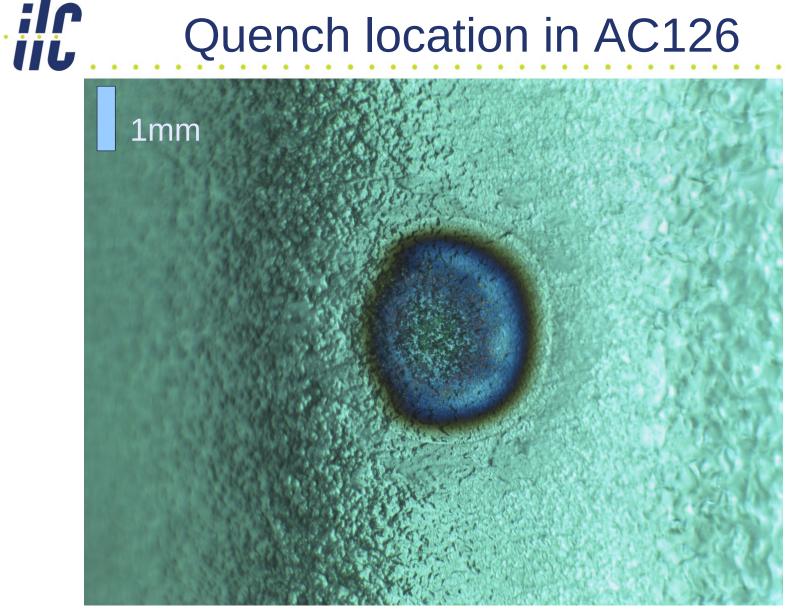
[D.Reschke]

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Sharp ridges at edge of defect

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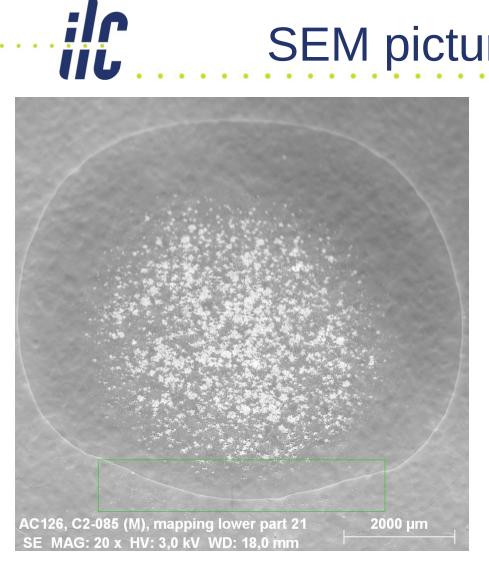
Quench location in AC126



Quench position indicated by 2nd sound: cell 2, t=85 deg, next to equator

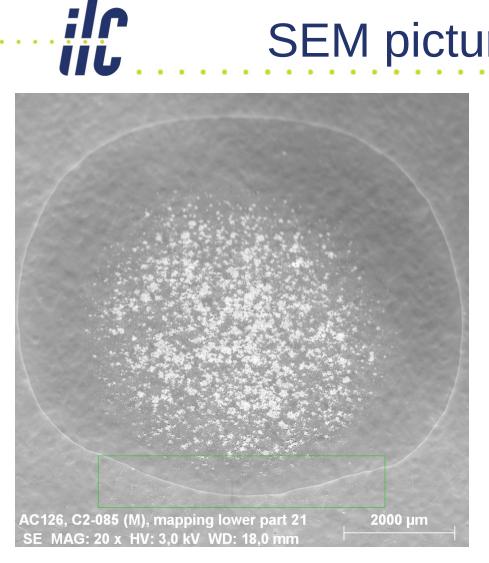
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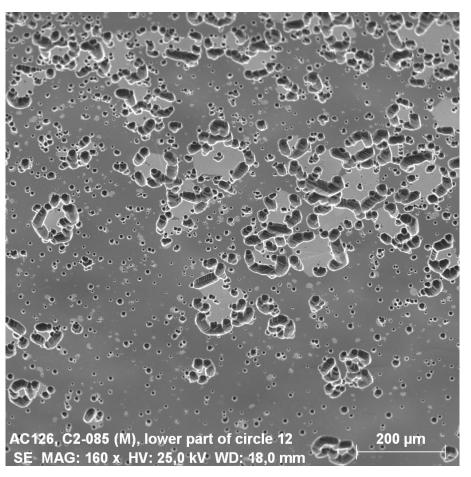
SEM pictures of defect



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SEM pictures of defect

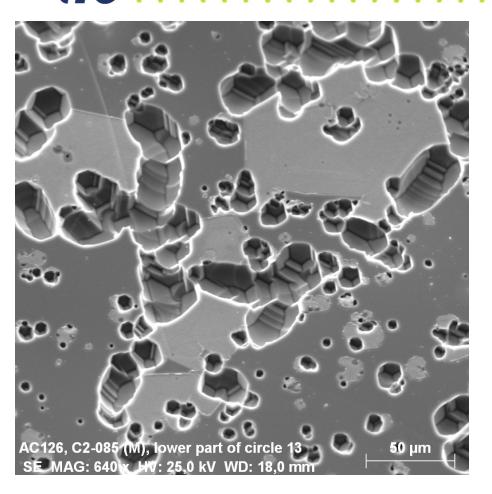




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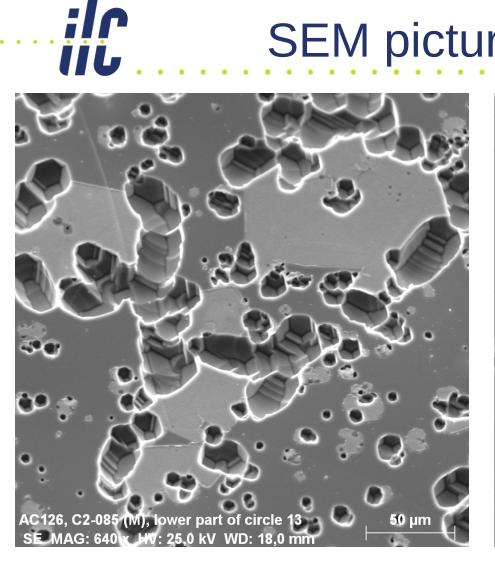
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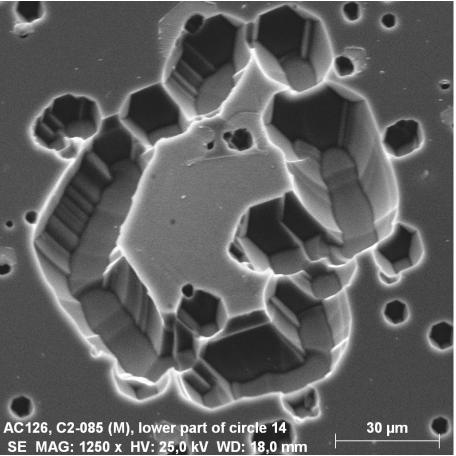
SEM pictures of defect



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SEM pictures of defect





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- Optical inspection system in very good use
- Correlations between optical inspection and limiting quench spots
- Cutting of cavities gave valuable information
- Automation of optical inspection for high throughput
 - L. Steder's talk
- Automation of defect recognition
 - M. Wenskat's talk

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